



WSR3002AF

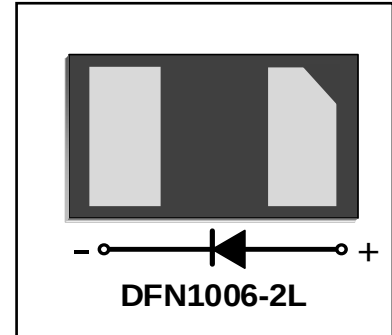
Schottky Barrier Diode

Features

- Small Outline Surface Mount Package
- RoHS Compliant / Green EMC

Applications

- Low Current Rectification
- Extremely Fast Switch Speed
- Inverse Polarity Protection
- Low Power Consumption Applications



Absolute Maximum Rating

Parameter	Symbol	Value	Unit
Peak Repetitive Peak Reverse Voltage	V_R	30	V
Power Dissipation	P_D	200	mW
Junction Temperature	T_J	125	°C
Storage Temperature	T_{stg}	-55 to 150	°C
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	500	°C/W

Electrical Characteristics ($T_{amb}=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Reverse Breakdown Voltage	V_{BR}	$I_R = 10\mu\text{A}$	30	-	-	V
Reverse Voltage Leakage Current	I_R	$V_R = 25\text{V}$	-	-	2	μA
Forward Voltage	V_F	$I_F = 0.1\text{mA}$	-	-	0.24	V
		$I_F = 1\text{mA}$	-	-	0.32	
		$I_F = 10\text{mA}$	-	-	0.4	
		$I_F = 30\text{mA}$	-	-	0.5	
		$I_F = 100\text{mA}$	-	-	1	
Typical Junction Capacitance	C_J	$V_R = 1\text{V}, f = 1.0\text{MHz}$	-	10	-	pF
Reverse Recovery Time	T_{rr}	$I_F = I_R = 10\text{mA}, I_{(REC)} = 1\text{mA}$	-	5	-	nS

Typical Characteristics

Figure 1. Forward Characteristics

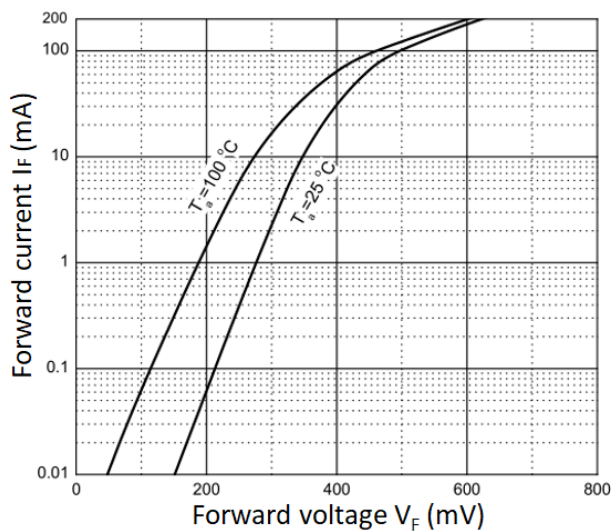


Figure 2. Reverse Characteristics

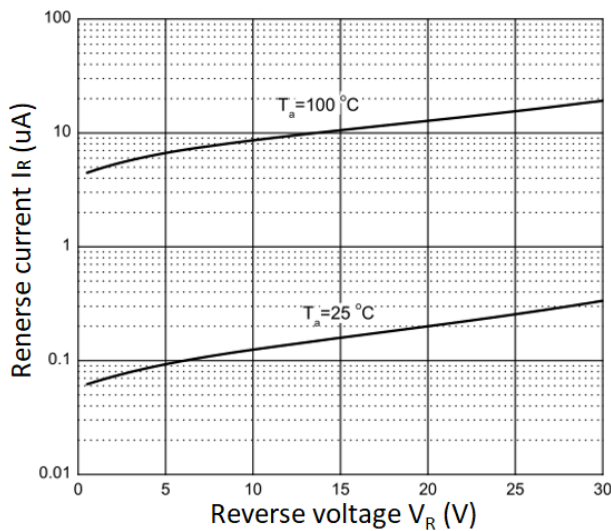


Figure 3. Capacitance Characteristics

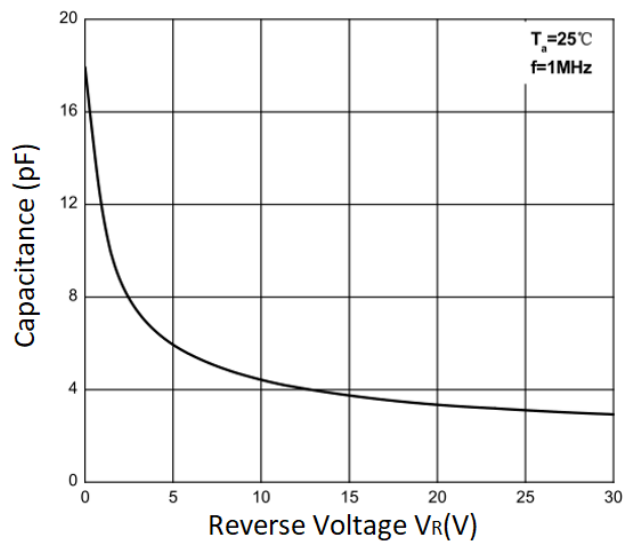
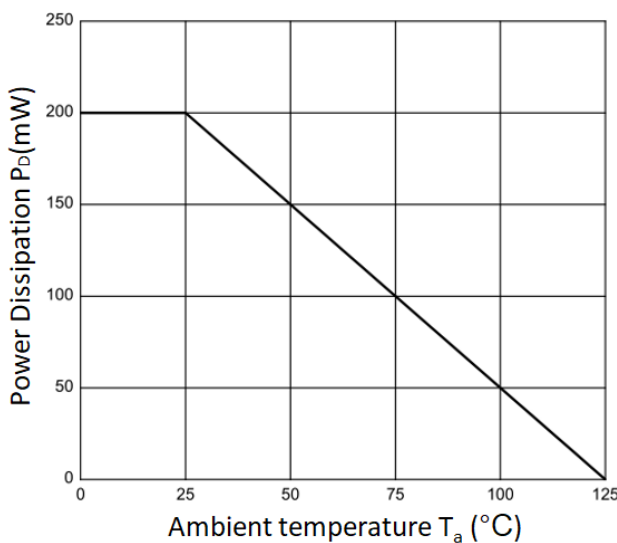
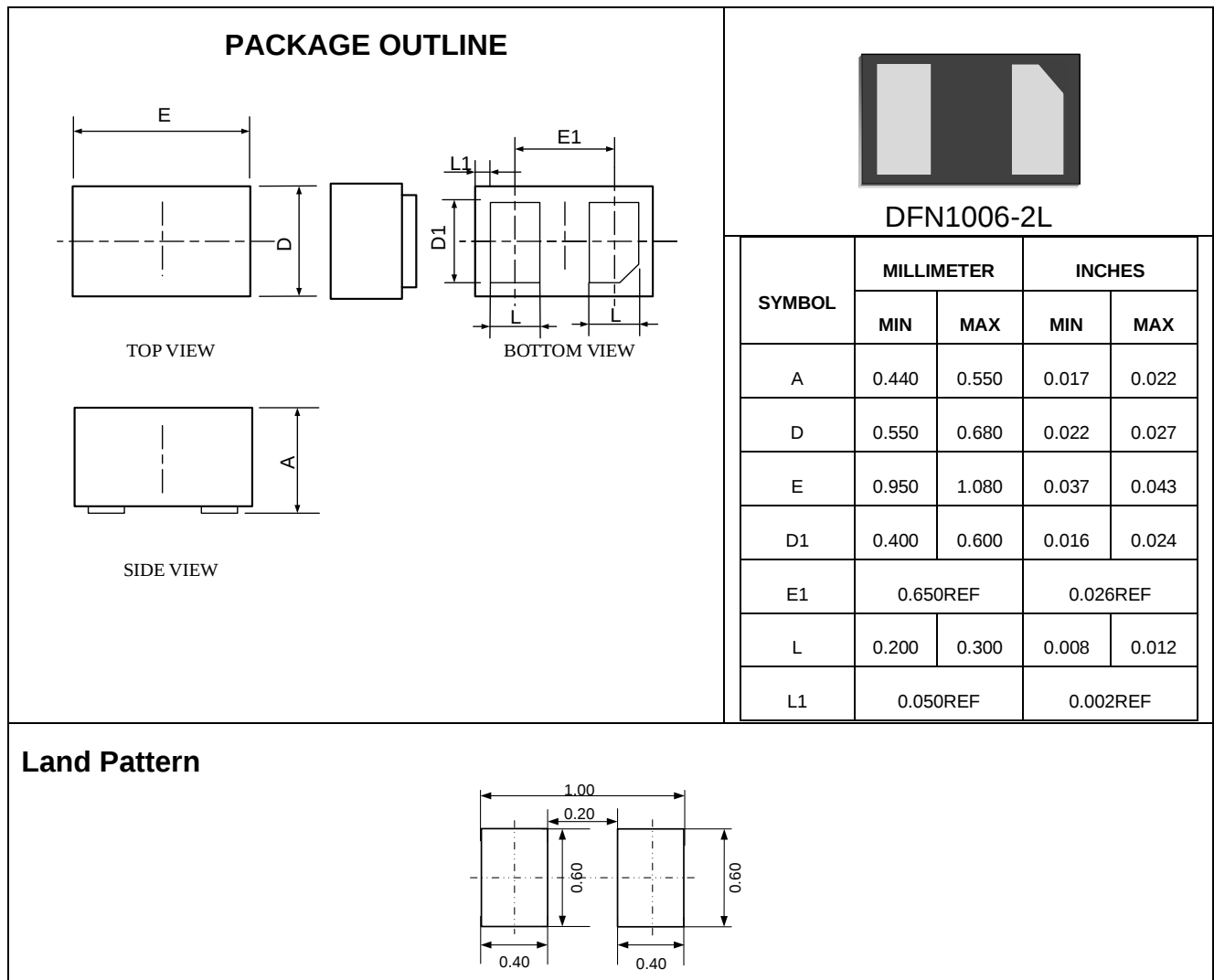


Figure 4. Power Derating Curve



Outline Drawing –DFN1006-2L



Marking Codes

Part Number	WSR3002AF
Marking Code	

Package Information

Qty: 10k/Reel

CONTACT INFORMATION

No.1001, Shiwan (7) Road, Pudong District, Shanghai, P.R.China.201207

Tel: 86-21-68969993 Fax: 86-21-50757680 Email: market@way-on.comWAYON website: <http://www.way-on.com>

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Specifications are subject to change without notice.

The device characteristics and parameters in this data sheet can and do vary in different applications and actual device performance may vary over time. Users should verify actual device performance in their specific applications.